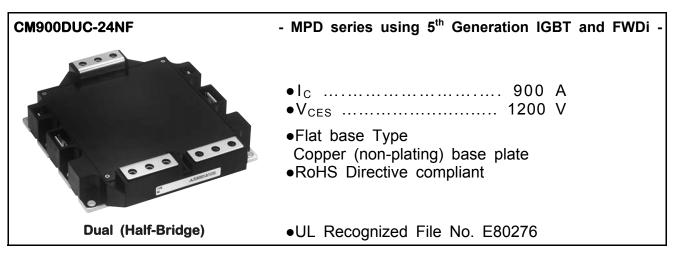
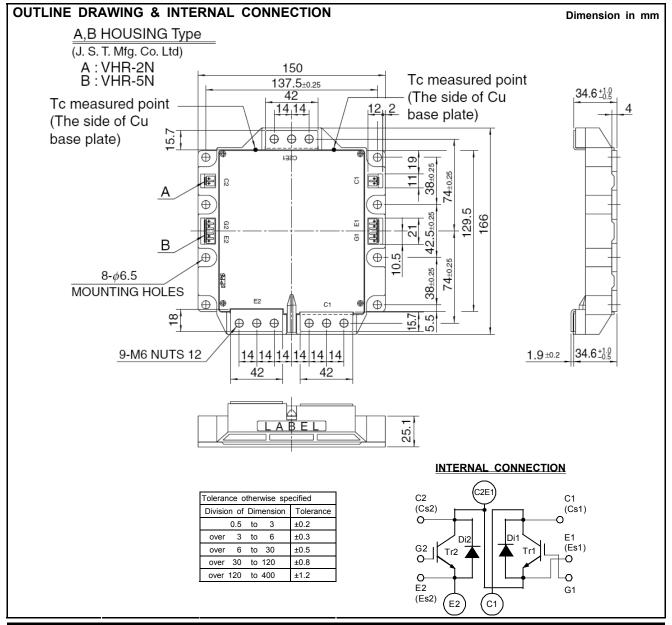
HIGH POWER SWITCHING USE INSULATED TYPE



APPLICATION

AC Motor Control, Motion/Servo Control, Power supply, etc.





MITSUBISHI IGBT MODULES

CM900DUC-24NF

HIGH POWER SWITCHING USE

INSULATED TYPE

ABSOLUTE MAXIMUM RATINGS (T_j=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit
V _{CES}	Collector-emitter voltage	G-E short-circuited	1200	V
V_{GES}	Gate-emitter voltage	C-E short-circuited	±20	V
Ic	Collector current	DC, T _C =96 °C ^(Note.2)	900	^
I _{CRM}		Pulse, Repetitive (Note.3)	1800	A
P _{tot}	Total power dissipation	T _C =25 °C ^(Note.2, 4)	5950	W
I _E (Note.1)	Emitter current	T _C =25 °C ^(Note.2, 4)	900	^
I _{ERM} (Note.1)	(Free wheeling diode forward current)	Pulse, Repetitive (Note.3)	1800	A
Tj	Junction temperature	-	-40 ~ +150	°C
T _{stg}	Storage temperature	(Note.7)	-40 ~ +125	
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	2500	V

ELECTRICAL CHARACTERISTICS (T_j =25 °C, unless otherwise specified)

Symbol	Item	Conditions			Limits		Unit
Symbol				Min.	Тур.	Max.	Unit
ICES	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circuited		-	-	1	mA
I _{GES}	Gate-emitter leakage current	±V _{GE} =V _{GES} , C-E short-circ	cuited	-	-	1	μA
$V_{GE(th)}$	Gate-emitter threshold voltage	I _C =90 mA, V _{CE} =10 V		6	7	8	V
V _{CEsat}	Collector-emitter saturation voltage	I _C =900 A ^(Note.5) ,	T _j =25 °C	-	1.8	2.5	V
	-	V _{GE} =15 V	T _j =125 °C	-	2.0	-	
Cies	Input capacitance			-	-	140	
Coes	Output capacitance	V _{CE} =10 V, G-E short-circu	uited	-	-	16	nF
Cres	Reverse transfer capacitance	1		-	-	3.0	
Q _G	Gate charge	V _{CC} =600 V, I _C =900 A, V _{GE}	V _{CC} =600 V, I _C =900 A, V _{GE} =15 V		4800	-	nC
t _{d(on)}	Turn-on delay time	V _{cc} =600 V, I _c =900 A, V		-	-	600	
tr	Rise time	- V _{CC} -000 V, I _C -900 A, V	_{GE} -113 V,	-	-	200	
t _{d(off)}	Turn-off delay time	D =0.25 O Industive less	4	-	-	800	ns
tf	Fall time	- R _G =0.35 Ω, Inductive load	1	-	-	300	
V _{EC} (Note.1)	Emitter-collector voltage	I _E =900 A ^(Note.5) , G-E sh	ort-circuited	-	2.5	3.2	V
t _{rr} ^(Note.1)	Reverse recovery time	V _{CC} =600 V, I _E =900 A, V _{GE}	=±15 V,	-	-	500	ns
Q _{rr} (Note.1)	Reverse recovery charge	R _G =0.35 Ω, Inductive lo	ad	-	50	-	μC
Eon	Turn-on switching energy per pulse	V _{CC} =600 V, I _C =I _E =900 A	·,	-	147.5	-	
E _{off}	Turn-off switching energy per pulse	V_{GE} =±15 V, R _G =0.35 Ω,	T _j =125 °C,	-	88	-	mJ
Err (Note.1)	Reverse recovery energy per pulse	Inductive load		-	91.8	-	1
R _{CC'+EE'}	Internal lead resistance	Main terminals-chip, per s T _C =25 °C (Note.2)	switch,	-	0.286	-	mΩ
r _g	Internal gate resistance	Per switch		-	1.0	-	Ω

THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
Symbol	nem	Conditions	Min.	Тур.	Max.	Onit
R _{th(j-c)Q}	Thermal resistance (Note.2)	Junction to case, per IGBT	-	-	21	K/kW
$R_{th(j-c)D}$	memaresistance	Junction to case, per FWDi	-	-	34	K/kW
R _{th(c-s)}	Contact thermal resistance (Note.2)	Case to heat sink, per 1/2 module, Thermal grease applied ^(Note.6)	-	12	-	K/kW

MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
Symbol	itelli	Conditions	Min.	Тур.	Max.	Offic
Mt	Mounting torque	Main terminals M 6 screw	3.5	4.0	4.5	N∙m
Ms	Mounting torque	Mounting to heat sink M 6 screw	3.5	4.0	4.5	IN'111
m	Weight	-	-	1450	-	g
ec	Flatness of base plate	On the centerline X, Y1, Y2 (Note.8)	-50	-	+100	μm



HIGH POWER SWITCHING USE

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RECOMMENDED OPERATING CONDITIONS (T_a=25 °C)

Symbol	Item	Conditions	Limits			Unit
Symbol	item	Conditions	Min.	Тур.	Max.	Unit
Vcc	(DC) Supply voltage	Applied across C1-E2	-	600	800	V
V_{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2	13.5	15.0	16.5	v
R _G	External gate resistance	Per switch	0.35	-	2.2	Ω

Note.1: Represent ratings and characteristics of the anti-parallel, emitter-collector free wheeling diode (FWDi).

Note.2: Case temperature (T_c) and heat sink temperature (T_s) are defined on the each surface of base plate and heat sink just under the chips. (Refer to the figure of chip location)

The heat sink thermal resistance $\{R_{th(s-a)}\}$ should measure just under the chips.

Note.3: Pulse width and repetition rate should be such that the device junction temperature (T_j) dose not exceed T_{jmax} rating. Note.4: Junction temperature (T_j) should not increase beyond T_{jmax} rating.

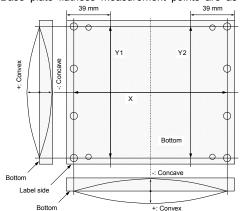
Note 5: Pulse width and repetition rate should be such as to cause negligible temperature rise.

(Refer to the figure of test circuit)

Note.6: Typical value is measured by using thermally conductive grease of λ =0.9 W/(m·K).

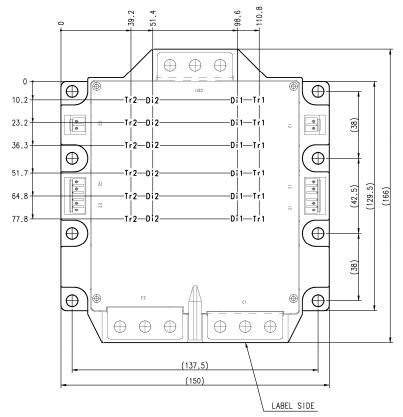
Note.7: The operation temperature is restrained by the permission temperature of female connector housing.

Note.8: Base plate flatness measurement points are as in the following figure.



CHIP LOCATION (Top view)

Dimension in mm, tolerance: ±1 mm



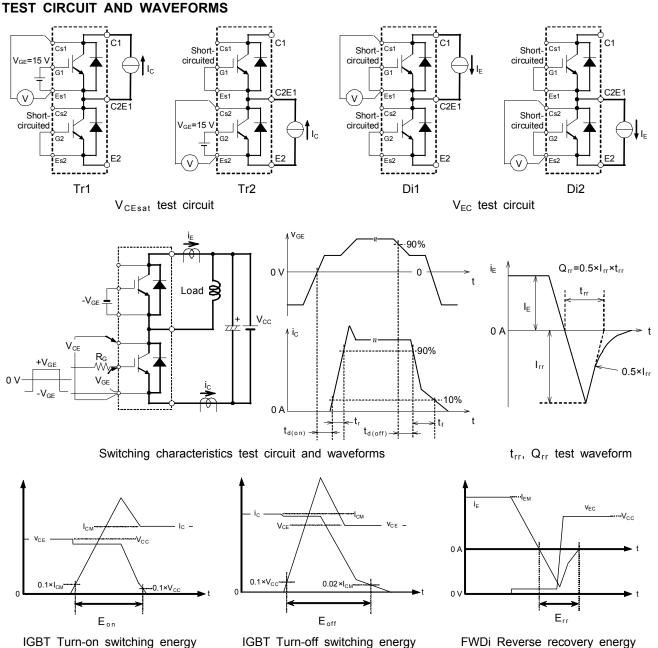
Tr1/Tr2: IGBT, Di1/Di2: FWDi. Each mark points the center position of each chip.



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CM900DUC-24NF HIGH POWER SWITCHING USE

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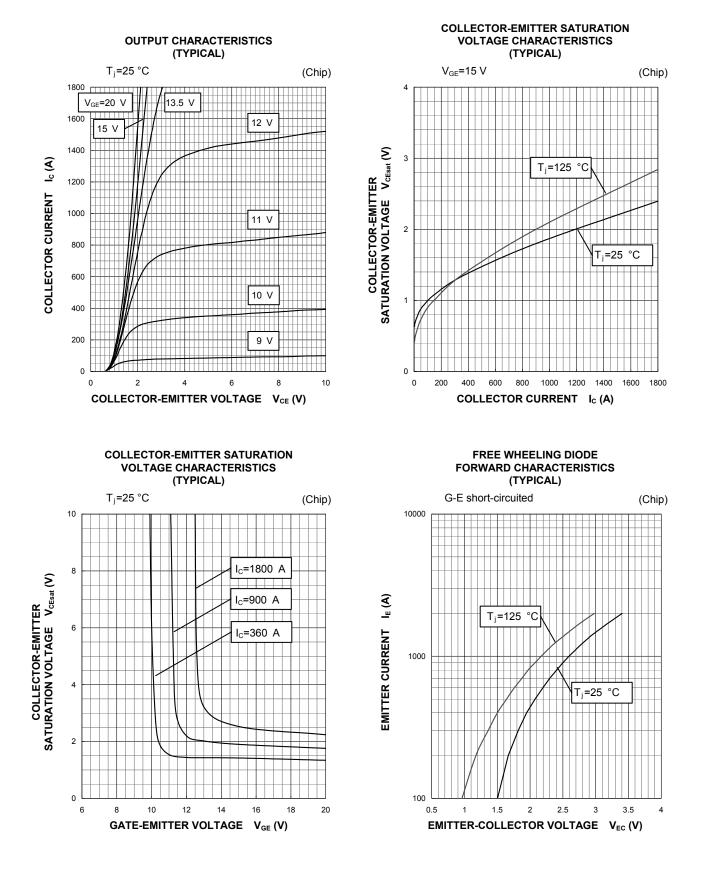
IGBT Turn-on switching energy IGBT Turn-off switching energy FWDi Reverse recovery energy Turn-on / Turn-off switching energy and Reverse recovery energy integral range



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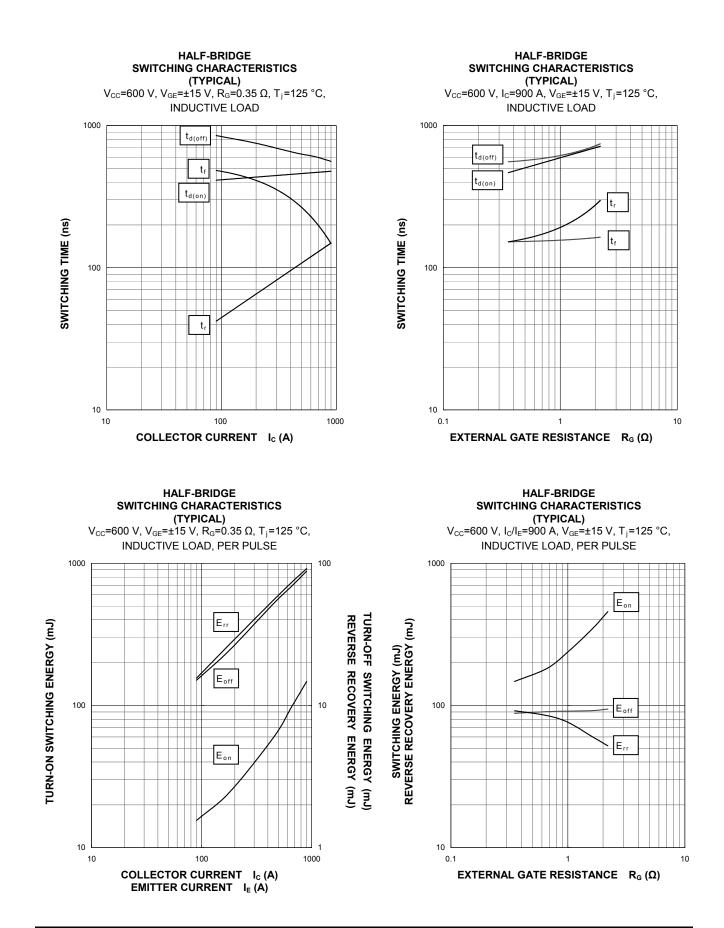
PERFORMANCE CURVES





MITSUBISHI IGBT MODULES

HIGH POWER SWITCHING USE INSULATED TYPE



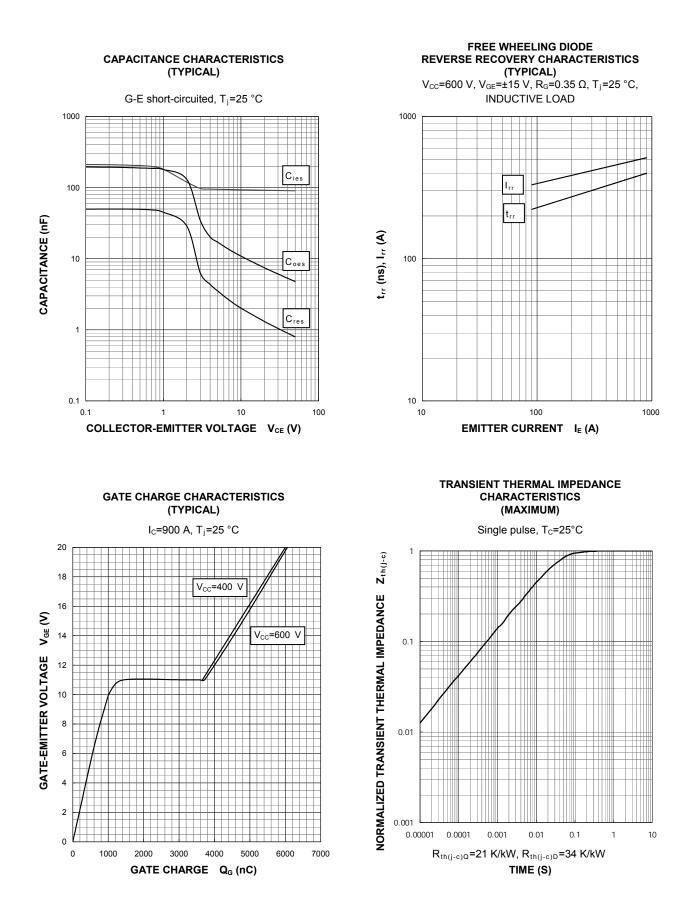


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MITSUBISHI IGBT MODULES CM900DUC-24NF

HIGH POWER SWITCHING USE

INSULATED TYPE





HIGH POWER SWITCHING USE INSULATED TYPE

Keep safety first in your circuit designs!

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